 	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/696,155	KIMURA ET AL.	
Examiner	Art Unit	
Mark Blouin	2627	

SEARCHED			
Class	Subclass	Date	Examiner
2/8	99.08	6/11/07	MB MB
248	672	6/11/07	M3
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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Jules	firec	6/1407	13

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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See EAST Text Seveled 260 See EAST	6/12/07	<i>~</i> 3
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